

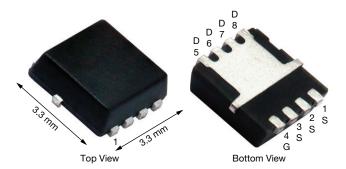
N-Channel 100 V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	100				
$R_{DS(on)}$ Typ. (Ω) at V_{GS} = 10 V	0.0174				
$R_{DS(on)}$ Typ. (Ω) at V_{GS} = 7.5 V	0.0205				
Q _g typ. (nC)	15.1				
I _D (A)	35.3 ^{a, g}				
Configuration	Single				

FEATURES

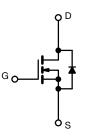
- TrenchFET[®] Gen IV power MOSFET
- Very low R_{DS} Q_g figure-of-merit (FOM)
- Tuned for the lowest R_{DS} $\mathsf{Q}_{\mathsf{oss}}$ FOM
- 100 % $\rm R_g$ and UIS tested





APPLICATIONS

- · Synchronous rectification
- · Primary side switch
- DC/DC converter
- Motor drive switch
- · Battery and load switch
- Industrial



N-Channel MOSFET

PARAMETER		SYMBOL	LIMIT	UNIT	
Drain-source voltage		V _{DS}	100	V	
Gate-source voltage		V _{GS}	± 20		
Continuous drain current (T _J = 150 °C)	T _C = 25 °C		35.3		
	T _C = 70 °C		28.2		
	T _A = 25 °C	I _D	9.4 ^{b, c}		
	T _A = 70 °C		7.5 ^{b, c}		
Pulsed drain current (t = 100 µs)		I _{DM}	80	— A	
Continuous source-drain diode current	T _C = 25 °C		47.2		
	T _A = 25 °C	I _S	3.3 b, c		
Single pulse avalanche current		I _{AS}	20		
Single pulse avalanche energy	L = 0.1 mH	E _{AS}	20	mJ	
Maximum power dissipation	T _C = 25 °C		52		
	T _C = 70 °C		33.3		
	T _A = 25 °C	P _D	3.7 ^{b, c}	W	
	T _A = 70 °C		2.4 ^{b, c}		
Operating junction and storage temperature range		T _J , T _{stg}	-55 to +150		
Soldering recommendations (peak temperature) ^c			260	°C	

THERMAL RESISTANCE RATINGS							
PARAMETER		SYMBOL	TYPICAL	MAXIMUM	UNIT		
Maximum junction-to-ambient ^b	t ≤ 10 s	R _{thJA}	24	33	°C/W		
Maximum junction-to-case (drain)	Steady state	R _{thJC}	1.9	2.4	C/W		

Notes a. Package limited

b. Surface mounted on 1" x 1" FR4 board

c. t = 10 s

d. The DFN3x3 package is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection

Rework conditions: manual soldering with a soldering iron is not recommended for leadless components Maximum under steady state conditions is 81 $^\circ$ C/W e. f.

g. T_C = 25 °C

PARAMETER	SYMBOL	TEST CONDITIONS	MIN.	TYP.	MAX.	UNIT	
Static							
Drain-source breakdown voltage	V _{DS}	$V_{GS} = 0 V, I_{D} = 250 \mu A$	100	-	-	V	
V _{DS} temperature coefficient	$\Delta V_{DS}/T_{J}$	I _D = 10 mA	-	81	-	1//20	
V _{GS(th)} temperature coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA	-	-7.5	-	mV/°C	
Gate-source threshold voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \ \mu A$	2	-	4	V	
Gate-source leakage	I _{GSS}	$V_{DS} = 0 V, V_{GS} = \pm 20 V$	-	-	100	nA	
Zero gate voltage drain current	I _{DSS}	$V_{DS} = 100 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	-	-	1	μΑ	
		V_{DS} = 100 V, V_{GS} = 0 V, T_{J} = 70 °C	-	-	15		
On-state drain current ^a	I _{D(on)}	$V_{DS} \geq 10 \text{ V}, \text{ V}_{GS} = 10 \text{ V}$	40	-	-	А	
Drain-source on-state resistance ^a	R _{DS(on)}	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 10 \text{ A}$	-	0.0174	-	Ω	
		$V_{GS} = 7.5 \text{ V}, \text{ I}_{D} = 10 \text{ A}$	_	0.0205	-		
Forward transconductance a	g _{fs}	$V_{DS} = 15 \text{ V}, \text{ I}_{D} = 10 \text{ A}$	-	46	-	S	
Dynamic ^b					•	•	
Input capacitance	C _{iss}	V _{DS} = 50 V, V _{GS} = 0 V, f = 1 MHz	-	1470	-	pF	
Output capacitance	C _{oss}		-	132	-		
Reverse transfer capacitance	C _{rss}		-	11.2	-		
Tatal acto charge	$V_{PC} = 50 \text{ V} V_{CC} = 10 \text{ V} I_{P}$	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$	-	20	30	nC	
Total gate charge	Qg		-	15.1	22.7		
Gate-source charge	Q _{gs}	V_{DS} = 50 V, V_{GS} = 7.5 V, I_{D} =10 A	-	6.45	-		
Gate-drain charge	Q _{gd}		-	3.5	-		
Output charge	Q _{oss}	$V_{DS} = 50 \text{ V}, \text{ V}_{GS} = 0 \text{ V}$	-	22	-		
Gate resistance	Rg	f = 1 MHz	0.2	0.76	1.4	Ω	
Turn-on delay time	t _{d(on)}		-	12	24		
Rise time	t _r	$V_{DD} = 50 \text{ V}, \text{ R}_{\text{I}} = 5 \Omega, \text{ I}_{\text{D}} \cong 10 \text{ A},$	-	5	10		
Turn-off delay time	t _{d(off)}	$V_{\text{GEN}} = 10$ V, $R_{\text{g}} = 1$ Ω	-	19	38		
Fall time	t _f		-	5	10		
Turn-on delay time	t _{d(on)}		-	15	30	ns	
Rise time	tr	V_{DD} = 50 V, R_L = 5 Ω , $I_D \cong$ 10 A,	-	6	12	-	
Turn-off delay time	t _{d(off)}	V_{GEN} = 7.5 V, R_g = 1 Ω	-	19	38		
Fall time	t _f		-	5	10		
Drain-Source Body Diode Characteristi	cs						
Continuous source-drain diode current	I _S	T _C = 25 °C	-	-	47.2	^	
Pulse diode forward current	I _{SM}		-	-	80	A	
Body diode voltage	V _{SD}	$I_{S} = 5 \text{ A}, V_{GS} = 0 \text{ V}$	-	0.78	1.1	V	
Body diode reverse recovery time	t _{rr}		-	43	86	ns	
Body diode reverse recovery charge	Q _{rr}		-	72	144	nC	
Reverse recovery fall time	ta	I _F = 10 A, di/dt = 100 A/μs, T _J = 25 °C	-	33	-		
Reverse recovery rise time	t _b		-	10	_	ns	

Notes

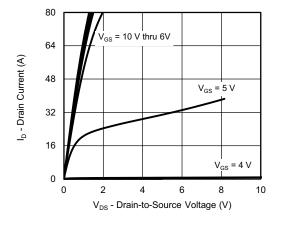
a. Pulse test; pulse width \leq 300 µs, duty cycle \leq 2 %

b. Guaranteed by design, not subject to production testing

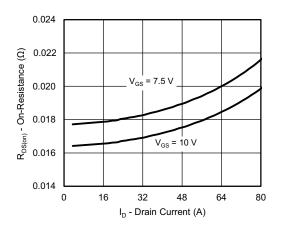
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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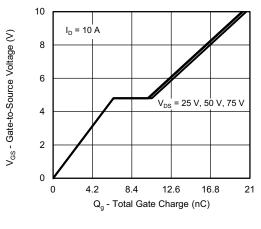




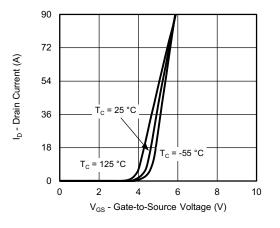
Output Characteristics



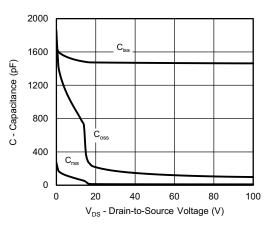
On-Resistance vs. Drain Current and Gate Voltage



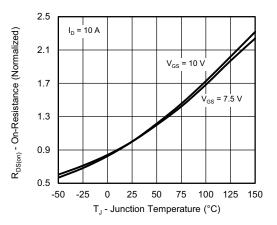
Gate Charge



Transfer Characteristics

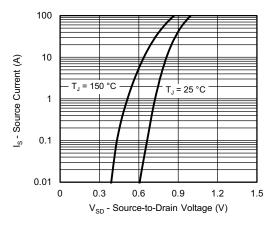


Capacitance

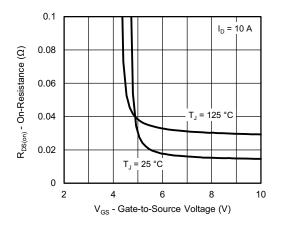


On-Resistance vs. Junction Temperature

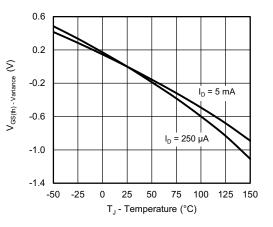




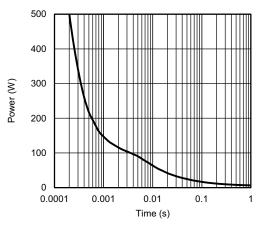
Source-Drain Diode Forward Voltage



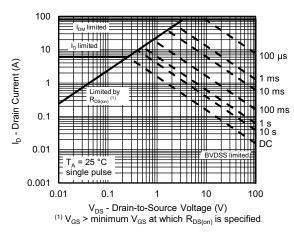
On-Resistance vs. Gate-to-Source Voltage



Threshold Voltage

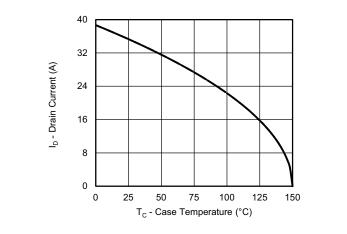


Single Pulse Power, Junction-to-Ambient

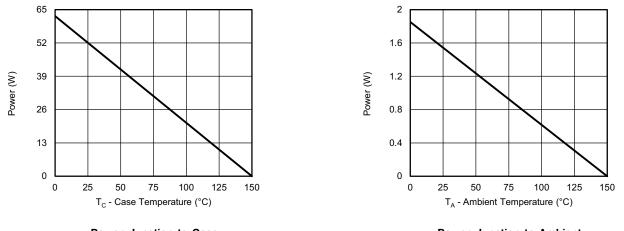


Safe Operating Area, Junction-to-Ambient





Current Derating ^a



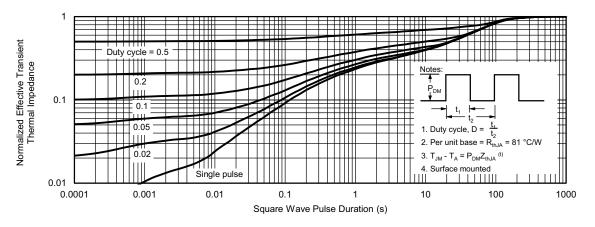
Power, Junction-to-Case

Power, Junction-to-Ambient

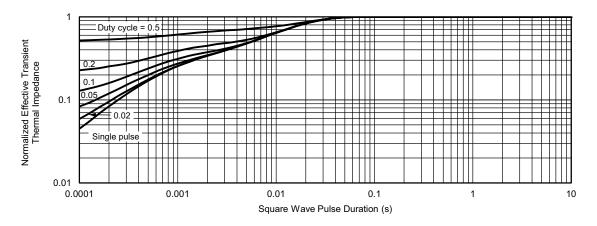
Note

a. The power dissipation P_D is based on T_J max. = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit





Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Case



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